

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/840,892	SATO ET AL.
	Examiner	Art Unit
	Tan Dean D. Nguyen	3629

SEARCHED			
Class	Subclass	Date	Examiner
205	1	7/1/05	oon
	7		
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	14 <sup>e</sup>		
	16 <sup>x</sup>		
	26 <sup>x</sup>		
	27 <sup>x</sup>		✓

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US	7/1/05	DN
1. PGPub 2. Patent	↓	↓
FOREIGN	7/1/05	↓
1. EPO 2. JPO 3. Derwent 4. IBM-TDB 5. USPTO CSR	↓	↓

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner